## Notice of References Cited Application/Control No. 10/731,722 Examiner David Sample Applicant(s)/Patent Under Reexamination TRAN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,914,026	07-2005	Tran et al.	502/66
*	В	US-6,689,709	02-2004	Tran et al.	502/65
*	С	US-2004/0242938	12-2004	Kanougi et al.	568/715
*	D	US-5,143,876	09-1992	Chang et al.	502/64
*	Ε	US-5,102,839	04-1992	Borghard et al.	502/66
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	7	US-			
	K	US-			
	الم	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν				,	
	0					4.
	Р					
	Q					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Mohamed et al., "Redox Behavior of Copper Mordenite Zeolite," JOURNAL OF MATERIALS SCIENCE, 30 (1995) 4834-4838.
	٧	Camblor et al., "Characterization of nanocrystalline zeolite Beta," MICROPOROUS AND MESOPOROUS MATERIALS, 25 (1998) 59-74.
	w	
	х	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.